

<b>Notice of References Cited</b>	Application/Control No. 10/784,785	Applicant(s)/Patent Under Reexamination NEJAD ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0165461	08-2004	Nejad et al.	365/203
	B	US-2004/0165421	08-2004	Nejad et al.	365/158
	C	US-2004/0057276	03-2004	Nejad et al.	365/158
	D	US-2004/0032760	02-2004	Baker, R. Jacob	365/148
	E	US-6,680,863	01-2004	Shi et al.	365/171
	F	US-6,829,188	12-2004	Baker, R. Jacob	365/205
	G	US-6,778,434	08-2004	Tsuji, Takaharu	365/173
	H	US-6,756,652	06-2004	Yano et al.	257/508
	I	US-6,373,753	04-2002	Proebsting, Robert J.	365/189.09
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP02002170376A	06-2002	Japan	Hidaka	G11C 11/15
*	O	WO.000241321A1	05-2002	European	Boehm et al	G11C 11/16
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U.	
	V	
	W	
	X	

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